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FDP8870

N-Channel PowerTrench[®] MOSFET 30V, 156A, 4.1m Ω

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\mbox{\scriptsize DS(ON)}}$ and fast switching speed.

Applications

DC/DC converters



Features

- $r_{DS(ON)} = 4.1 \text{m}\Omega$, $V_{GS} = 10 \text{V}$, $I_D = 35 \text{A}$
- $r_{DS(ON)} = 4.6 m\Omega$, $V_{GS} = 4.5 V$, $I_D = 35 A$
- High performance trench technology for extremely low r_{DS(ON)}
- · Low gate charge
- · High power and current handling capability
- · RoHS Compliant







MOSFET Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Ratings	Units V	
V _{DSS}	Drain to Source Voltage	30		
V _{GS}	Gate to Source Voltage	±20	V	
	Drain Current			
I _D	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$) (Note 1)	156	Α	
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4.5V$) (Note 1)	147	А	
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 62^{\circ}C/W$)	19	А	
	Pulsed	Figure 4	А	
E _{AS}	Single Pulse Avalanche Energy (Note 2)	300	mJ	
	Power dissipation	160	W	
P_{D}	Derate above 25°C	1.07	W/°C	
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C	

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-220	0.94	°C/W
R _{e,IA}	Thermal Resistance Junction to Ambient TO-220 (Note 3)	62	°C/W

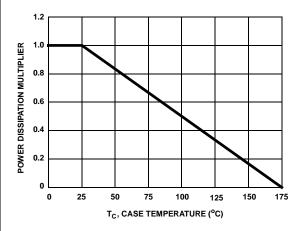
Package Marking and Ordering Information

Device Marking Device		Package	Package Reel Size		Quantity	
FDP8870	FDP8870	TO-220AB	Tube	N/A	50 units	

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Chara	cteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$		30	-	-	V
	Zara Cata Vallana Basis Comant	$V_{DS} = 24V$		-	-	1	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}{\rm C}$	-	-	250	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nΑ
On Chara	cteristics						
V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 2$.50μA	1.2	-	2.5	V
		I _D = 35A, V _{GS} = 10V		-	0.0034	0.0041	
-	Drain to Source On Resistance	$I_D = 35A, V_{GS} = 4$		-	0.0040	0.0046	
r _{DS(ON)}	Diam to Source On Resistance	$I_D = 35A, V_{GS} = 10V,$ $T_{LI} = 175^{\circ}C$		-	0.0051	0.0065	Ω
Dynamic	Characteristics						
C _{ISS}	Input Capacitance	1/ 45)/)/	0)/	-	5200	-	pF
C _{OSS}	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ $f = 1MHz$		-	970	-	pF
C _{RSS}	Reverse Transfer Capacitance			-	570	-	pF
R _G	Gate Resistance	$V_{GS} = 0.5V, f = 1N$	ИHz	-	2.1	-	Ω
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{GS} = 0V \text{ to } 10V$		-	106	132	nC
Q _{g(5)}	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$		-	56	69	nC
Q _{g(TH)}	Threshold Gate Charge	\/ - 0\/ to 1\/	$V_{DD} = 15V$	-	5.0	6.5	nC
Q _{gs}	Gate to Source Gate Charge	$I_{D} = 35A$ $I_{g} = 1.0 \text{mA}$		-	15	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau			-	10	-	nC
Q_{gd}	Gate to Drain "Miller" Charge			-	23	-	nC
Switching	Characteristics (V _{GS} = 10V)						
t _{ON}	Turn-On Time			-	-	168	ns
t _{d(ON)}	Turn-On Delay Time			-	11	-	ns
t _r	Rise Time	$V_{DD} = 15V, I_{D} = 35A$ $V_{GS} = 4.5V, R_{GS} = 3.3\Omega$		-	105	-	ns
t _{d(OFF)}	Turn-Off Delay Time			-	70	-	ns
t _f	Fall Time			-	46	-	ns
t _{OFF}	Turn-Off Time			-	-	173	ns
Drain-Soເ	urce Diode Characteristics						
V _{SD}	Source to Drain Diade Velters	I _{SD} = 35A		-	-	1.25	V
	Source to Drain Diode Voltage	I _{SD} = 15A		-	-	1.0	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 35A$, dI_{SD}/dt	t = 100A/μs	-	-	37	ns
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 35A$, dI_{SD}/dt		_	T -	21	nC

- Notes:
 1: Package current limitation is 80A.
 2: Starting T_J = 25°C, L = 0.15mH, I_{AS} = 64A, V_{DD} = 27V, V_{GS} = 10V.
 3: Pulse width = 100s.





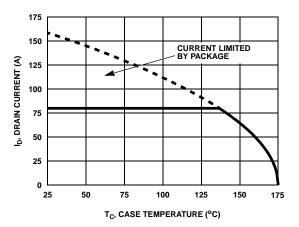


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

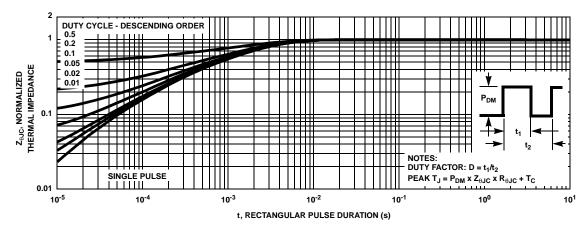


Figure 3. Normalized Maximum Transient Thermal Impedance

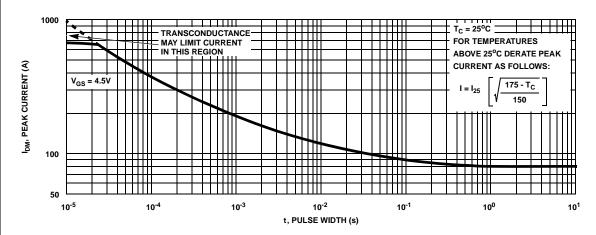
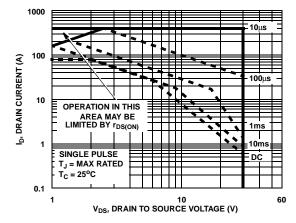


Figure 4. Peak Current Capability

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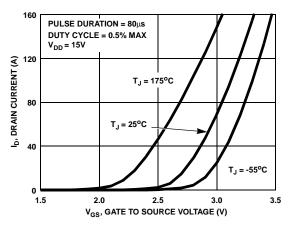
 $\begin{array}{c} 500 \\ \hline \\ 100 \\ \hline$

Figure 5. Forward Bias Safe Operating Area

NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability



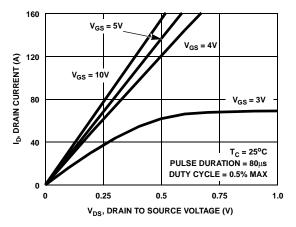
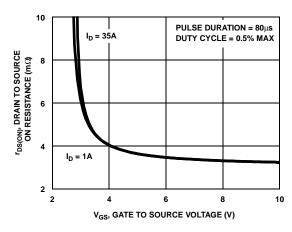


Figure 7. Transfer Characteristics

Figure 8. Saturation Characteristics



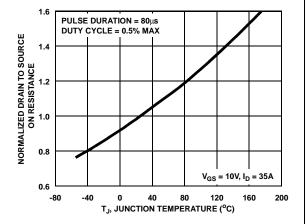


Figure 9. Drain to Source On Resistance vs Gate Voltage and Drain Current

Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

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Typical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

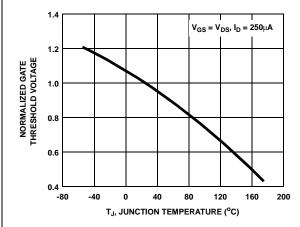


Figure 11. Normalized Gate Threshold Voltage vs
Junction Temperature

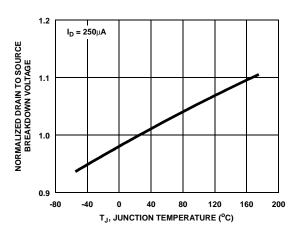


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

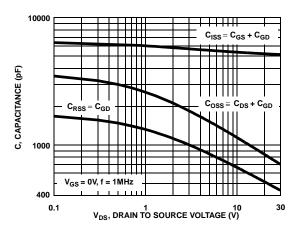


Figure 13. Capacitance vs Drain to Source Voltage

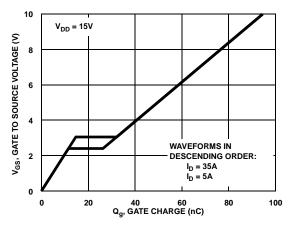


Figure 14. Gate Charge Waveforms for Constant Gate Current

Test Circuits and Waveforms

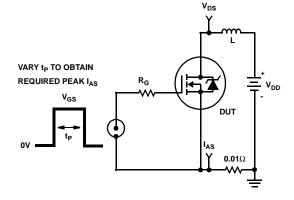


Figure 15. Unclamped Energy Test Circuit

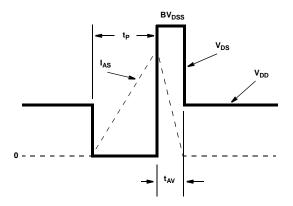


Figure 16. Unclamped Energy Waveforms

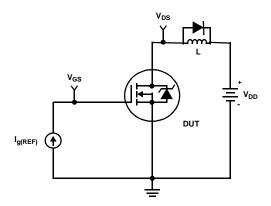


Figure 17. Gate Charge Test Circuit

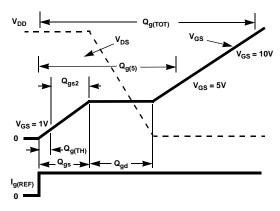


Figure 18. Gate Charge Waveforms

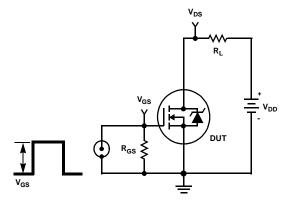


Figure 19. Switching Time Test Circuit

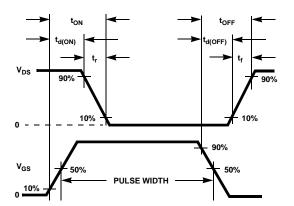


Figure 20. Switching Time Waveforms

PSPICE Electrical Model .SUBCKT FDP8870 2 1 3 ; rev December 2003 Ca 12 8 4.5e-9 Cb 15 14 4.5e-9 LDRAIN DPLCAP DRAIN Cin 6 8 4.7e-9 10 Dbody 7 5 DbodyMOD RLDRAIN RSLC1 Dbreak 5 11 DbreakMOD DBREAK Dplcap 10 5 DplcapMOD RSLC2 ≤ FSI C 11 Ebreak 11 7 17 18 33.45 50 Eds 14 8 5 8 1 Egs 13 8 6 8 1 ■ DBODY RDRAIN **EBREAK ESG** Esa 6 10 6 8 1 **FVTHRES** Evthres 6 21 19 8 1 $\left(\frac{19}{8}\right)$ Evtemp 20 6 18 22 1 MWFAK LGATE **EVTEMP** GATE **RGATE** ____ (18 22 匤 It 8 17 1 MMFD 9 20 MSTRO RIGATE Lgate 1 9 3.6e-9 LSOURCE CIN SOURCE Ldrain 2 5 1.0e-9 Lsource 3 7 3.3e-9 RSOURCE RLSOURCE RLgate 1 9 36 RBREAK RLdrain 2 5 10 14 13 13 8 18 RLsource 3 7 33 RVTEMP S1B Mmed 16 6 8 8 MmedMOD СВ 19 CA Mstro 16 6 8 8 MstroMOD IT 14 Mweak 16 21 8 8 MweakMOD VBAT EGS **EDS** Rbreak 17 18 RbreakMOD 1 8 Rdrain 50 16 RdrainMOD 2.15e-3 **RVTHRES** Rgate 9 20 2.1 RŠLC1 5 51 RSLCMOD 1e-6 RSLC2 5 50 1e3 Rsource 8 7 RsourceMOD 9e-4 Rvthres 22 8 RvthresMOD 1 Rvtemp 18 19 RvtempMOD 1 S1a 6 12 13 8 S1AMOD S1b 13 12 13 8 S1BMOD S2a 6 15 14 13 S2AMOD S2b 13 15 14 13 S2BMOD Vbat 22 19 DC 1 ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*500),10))} .MODEL DbodyMOD D (IS=7.5E-12 IKF=17 N=1.01 RS=2.1e-3 TRS1=2e-3 TRS2=2e-7 + CJO=1.9e-9 M=0.57 TT=9e-11 XTI=2.6) MODEL DbreakMOD D (RS=8e-2 TRS1=1e-3 TRS2=-8.9e-6) .MODEL DplcapMOD D (CJO=1.75e-9 IS=1e-30 N=10 M=0.4) .MODEL MmedMOD NMOS (VTO=2.1 KP=30 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=2.1 T ABS=25) .MODEL MstroMOD NMOS (VTO=2.51 KP=650 IS=1e-30 N=10 TOX=1 L=1u W=1u T ABS=25) .MODEL MweakMOD NMOS (VTO=1.67 KP=0.1 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=21 RS=0.1 T_ABS=25) .MODEL RbreakMOD RES (TC1=8.3e-4 TC2=-9e-7) .MODEL RdrainMOD RES (TC1=2.3e-3 TC2=5e-6) MODEL RSLCMOD RES (TC1=1e-4 TC2=1e-6) .MODEL RsourceMOD RES (TC1=8e-3 TC2=1e-6) .MODEL RvthresMOD RES (TC1=-2.3e-3 TC2=-9e-6) .MODEL RytempMOD RES (TC1=-3e-3 TC2=2e-7) .MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-4 VOFF=-2) .MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2 VOFF=-4) .MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-1 VOFF=-0.5) .MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-0.5 VOFF=-1) **FNDS** Note: For further discussion of the PSPICE model, consult A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

SABER Electrical Model rev December 2003 template FDP8870 n2,n1,n3 =m temp electrical n2,n1,n3 number m_temp=25 var i iscl $dp..model\ dbodymod = \ (isl=7.5e-12,ikf=17,nl=1.01,rs=2.1e-3,trs1=2e-3,trs2=2e-7,cjo=1.9e-9,m=0.57,tt=9e-11,xti=2.6)$ dp..model dbreakmod = (rs=8e-2,trs1=1e-3,trs2=-8.9e-6) dp..model dplcapmod = (cjo=1.75e-9,isl=10e-30,nl=10,m=0.4) $m..model mmedmod = (type=_n, vto=2.1, kp=30, is=1e-30, tox=1)$ m..model mstrongmod = (type= n,vto=2.51,kp=650,is=1e-30, tox=1) m..model mweakmod = (type=_n,vto=1.67,kp=0.1,is=1e-30, tox=1,rs=0.1) LDRAIN sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-4,voff=-2) **DPLCAP** DRAIN sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-2,voff=-4) 10 sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-1,voff=-0.5) RLDRAIN sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-0.5,voff=-1) RSLC1 c.ca n12 n8 = 4.5e-951 RSLC2 € c.cb n15 n14 = 4.5e-9ISCI c.cin n6 n8 = 4.7e-9DBREAK dp.dbody n7 n5 = model=dbodymod RDRAIN <u>6</u>8 dp.dbreak n5 n11 = model=dbreakmod **FSG** DBODY dp.dplcap n10 n5 = model=dplcapmod **EVTHRES** (<u>19</u>) **MWEAK** LGATE **EVTEMP** spe.ebreak n11 n7 n17 n18 = 33.45 _{GATE} **ММ**ЕД 18 22 EBREAK spe.eds n14 n8 n5 n8 = 1 spe.egs n13 n8 n6 n8 = 1 **←**MSTRC RLGATE spe.esg n6 n10 n6 n8 = 1 LSOURCE spe.evthres n6 n21 n19 n8 = 1 CIN SOURCE spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1 RBREAK I.lgate n1 n9 = 3.6e-9I.Idrain n2 n5 = 1.0e-9**₹**RVTEMP S1B oS2B I.Isource n3 n7 = 3.3e-919 СА IT (♠ 14 res.rlgate n1 n9 = 36 VBAT res.rldrain n2 n5 = 10 **EGS EDS** res.rlsource n3 n7 = 33 m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u, temp=m_temp **RVTHRES** m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u, temp=m_temp m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u, temp=m_temp res.rbreak n17 n18 = 1, tc1=8.3e-4,tc2=-9e-7 res.rdrain n50 n16 = 2.15e-3, tc1=2.3e-3,tc2=5e-6 res.rgate n9 n20 = 2.1res.rslc1 n5 n51 = 1e-6, tc1=1e-4,tc2=1e-6 res.rslc2 n5 n50 = 1e3res.rsource n8 n7 = 9e-4, tc1=8e-3,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-2.3e-3,tc2=-9e-6 res.rvtemp n18 n19 = 1. tc1=-3e-3.tc2=2e-7sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/500))** 10))

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PSPICE Thermal Model JUNCTION REV 23 December 2003 FDP8870T CTHERM1 TH 6 1e-3 CTHERM2 6 5 2e-3 CTHERM3 5 4 3e-3 RTHERM1 CTHERM1 CTHERM4 4 3 9e-3 CTHERM5 3 2 1e-2 CTHERM6 2 TL 2e-2 RTHERM1 TH 6 3e-2 RTHERM2 6 5 8e-2 RTHERM3 5 4 1.1e-1 RTHERM2 CTHERM2 RTHERM4 4 3 1.6e-1 RTHERM5 3 2 1.72e-1 RTHERM6 2 TL 2e-1 5 SABER Thermal Model SABER thermal model FDP8870T RTHERM3 CTHERM3 template thermal_model th tl thermal_c th, tl ctherm.ctherm1 th 6 =1e-3 ctherm.ctherm2 6 5 = 2e-3 ctherm.ctherm3 5 4 =3e-3 ctherm.ctherm4 4 3 =9e-3 ctherm.ctherm5 3 2 =1e-2 RTHERM4 CTHERM4 ctherm.ctherm6 2 tl =2e-2 rtherm.rtherm1 th 6 =3e-2 rtherm.rtherm2 6 5 =8e-2 3 rtherm.rtherm3 5 4 =1.1e-1 rtherm.rtherm4 4 3 =1.6e-1 rtherm.rtherm5 3 2 =1.72e-1 RTHERM5 CTHERM5 rtherm.rtherm6 2 tl =2e-1 2 RTHERM6 CTHERM6 CASE tl





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